



URSI GASS 2021

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On the Feasibility of Using Inverse Scattering to Optimize the Design of EBG Devices

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OUTLINE

- Inverse Scattering as a design tool and the inherent issues
- Forward problem for a random set of (small) parallel cylinders: the scattering matrix method (SMM)
- Synthesis of EBG devices through the SMM

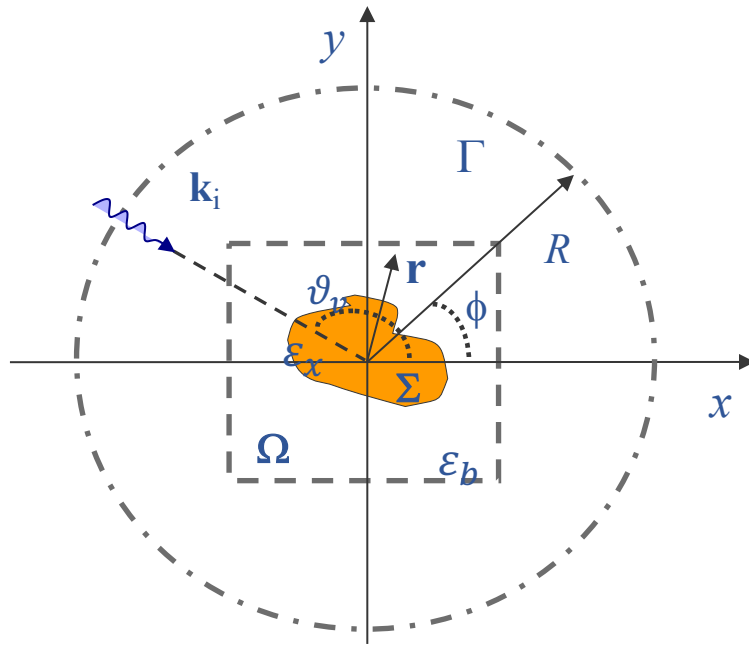
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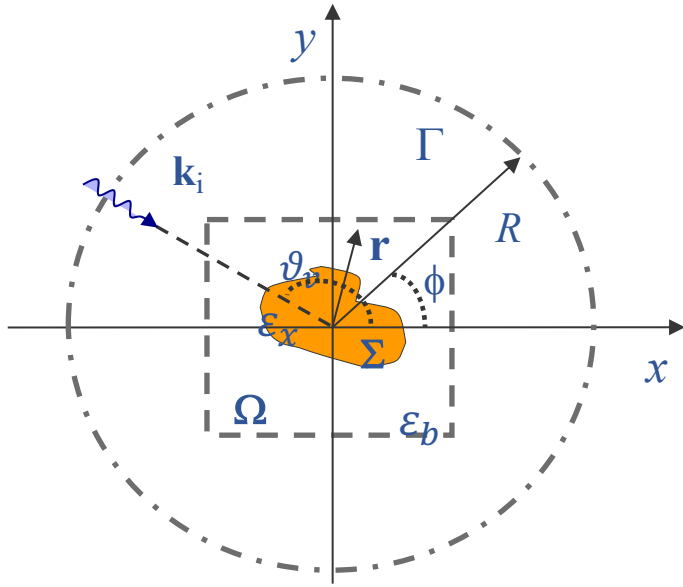
inverse scattering problem (ISP)

Let be :

- Ω the region under investigation embedding the unknown target Σ
- Γ the observation domain; it is usually a surface enclosing Ω
- $E_i(\mathbf{r}, \mathbf{r}_t)$ the incident field illuminating Ω from \mathbf{r}_t impinging directions
- $E_s(\mathbf{r}_m, \mathbf{r}_t)$ the scattered field measured at \mathbf{r}_m observation directions in Γ , due to the induced contrast source $\mathbf{W}(\mathbf{r}, \mathbf{r}_t)$ inside Ω



inverse scattering problem (ISP)



$$E_i(\mathbf{r}, \mathbf{r}_t), E_s(\mathbf{r}_m, \mathbf{r}_t)$$

$$\mathbf{r} \in \Omega, \mathbf{r}_t, \mathbf{r}_m \in \Gamma$$



$$\chi(\mathbf{r}) = \frac{\epsilon_x(\mathbf{r})}{\epsilon_b(\mathbf{r})} - 1$$

CONTRAST FUNCTION
encodes target properties
(e.m. parameters, shape)

The inverse scattering problem is described by two main equations :

CONTRAST SOURCE $W = \chi E$

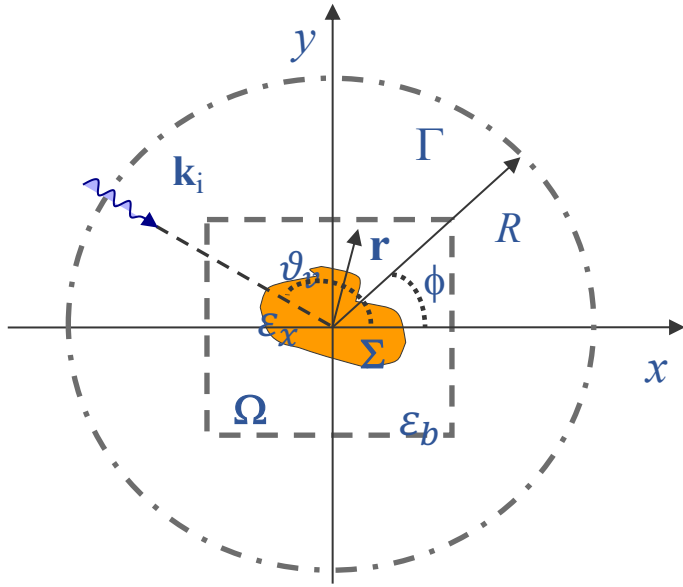
$$E_s(\mathbf{r}_m, \mathbf{r}_t) = \mathcal{A}_e[W(\mathbf{r}, \mathbf{r}_t)] \quad \text{'data equation'}$$

$$\mathbf{r} \in \Omega, \mathbf{r}_m, \mathbf{r}_t \in \Gamma$$

$$W(\mathbf{r}, \mathbf{r}_t) = \chi E_i(\mathbf{r}, \mathbf{r}_t) + \chi \mathcal{A}_i[W(\mathbf{r}, \mathbf{r}_t)] \quad \text{'state equation'}$$

NOTE: χ and W are unknowns ! The only available data are E_i and E_s .

inverse scattering problem (ISP)



$$E_i(\mathbf{r}, \mathbf{r}_t), E_s(\mathbf{r}_m, \mathbf{r}_t)$$

$$\mathbf{r} \in \Omega, \mathbf{r}_t, \mathbf{r}_m \in \Gamma$$



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non-linear and **ill-posed** inverse problem

Inverse Scattering as a design tool

THE USUAL AIM:

Given a set of incident fields, find the e.m. characteristics of the region under test (i.e., $\chi(r)$) in such a way that the scattered (total) field obeys the collected measurements

Inverse Scattering as a design tool

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A DIFFERENT AIM:

Given a set of incident fields, find the e.m. characteristics of the region under test (i.e., $\chi(r)$) in such a way that the scattered (total) field obeys to given specifications

Inverse Scattering as a design tool

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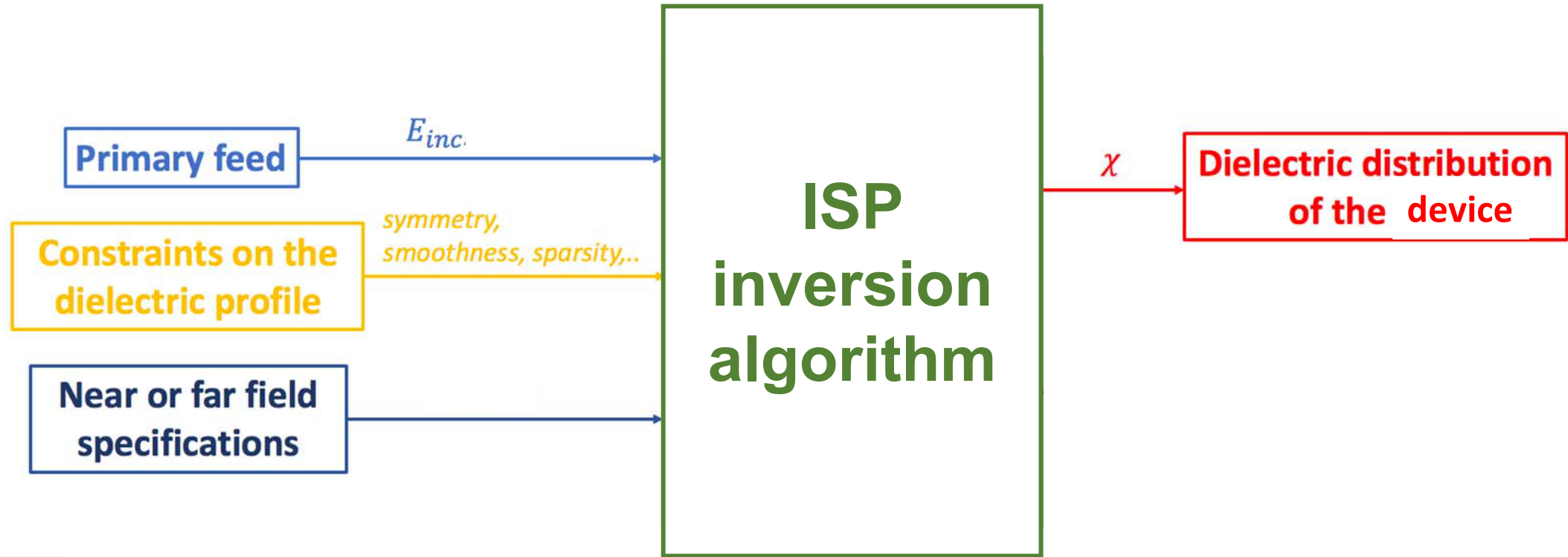
A DIFFERENT AIM:

Given a set of incident fields, find the e.m. characteristics of the region under test (i.e., $\chi(r)$) in such a way that the scattered (total) field obeys to given specifications

Inverse scattering theory and solution procedures can be seen as a design tool rather than as a mean for recovery/imaging

Innovative devices can be hopefully designed

ISP-based design procedure



Manufacturing a GRIN (GRADED refractive index) device is not a trivial task

Sometimes, homogenization techniques do not work

A design example: direct synthesis of a Graded Artificial Material (GAM)-based device

A novel expansion for the contrast function allowing the direct synthesis of GAM-based device

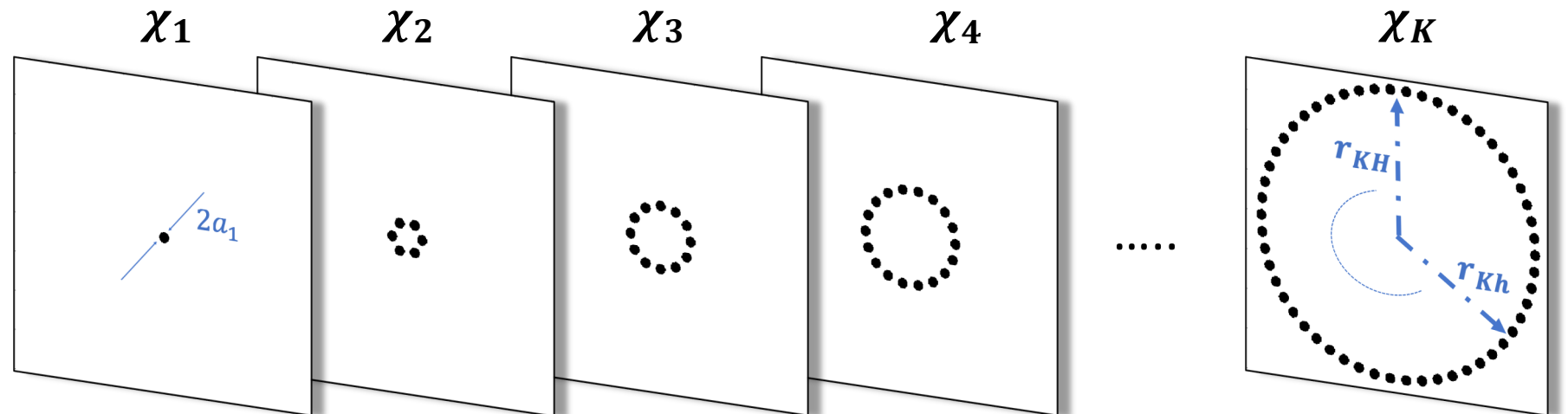
$$\chi(\mathbf{r}) = \sum_{k=1}^K \chi_k \Pi(\mathbf{r})$$

$\Pi(\mathbf{r})$ is the representation basis projecting χ into the space of 'inclusions'

χ_k coefficients are the new unknowns of the problem

GAM with a gradient of the refractive index (GAM_R)

$$\chi(\mathbf{r}) = \sum_{k=1}^K \chi_k \sum_{h=1}^{H_k} \Pi_{kh} \left(\frac{\mathbf{r} - \mathbf{r}_{kh}}{a_k} \right)$$



Pro and Cos of the ISP-based GAM design

- Dielectric profiles obeying non-canonical solutions
- Dielectric profiles satisfying desired spatial distributions constraints
- *Multi-view* Inverse Scattering Problems turn into *multi-purpose* device
- **Most of inversion algorithms are based on discretization of the investigation domain in subdomains/cells and are not suitable for GAM design.**

Smaller and smaller mesh elements → higher and higher number of unknowns

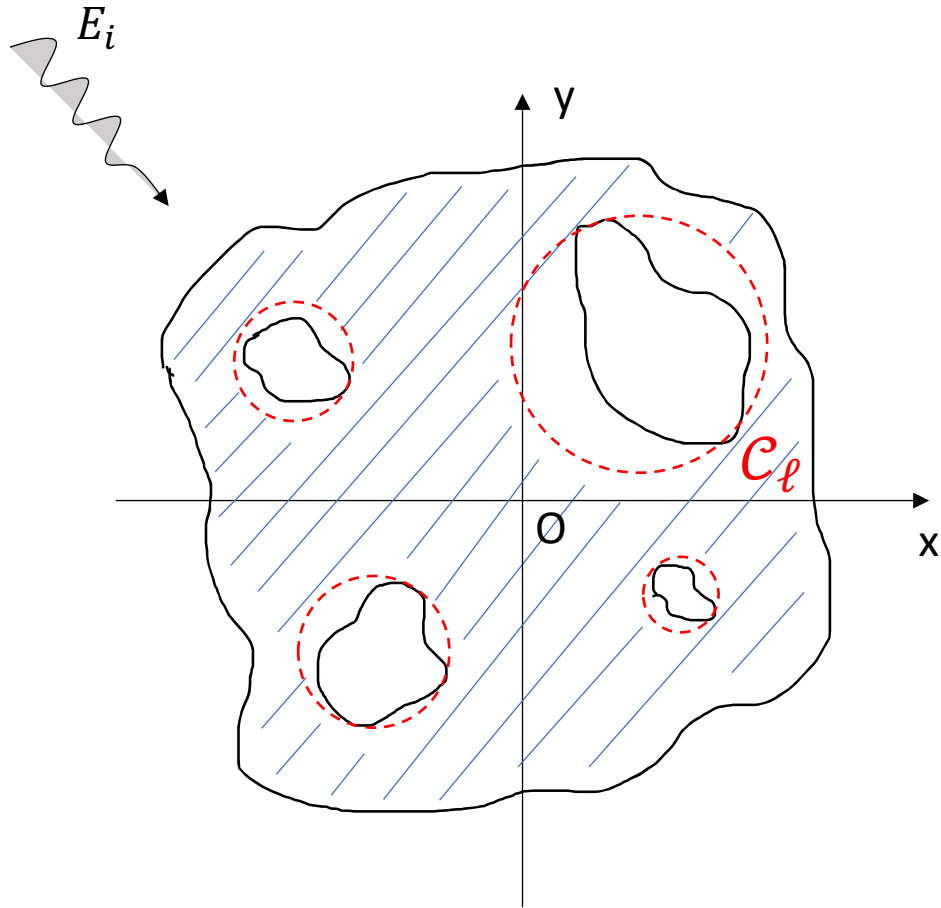
Staircasing errors

- **Less flexibility with respect to the ‘kind’ of unknowns** (radius, position of the inclusions)

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Multiple scatterers oriented tool: Scattering Matrix Method (SMM)



Modal expansion of the total field outside cylinders

$$E_{tot}(\underline{r}) = \sum_{m=-\infty}^{+\infty} a_{\ell,m} J_m(kr_{\ell}) e^{jm\theta_{\ell}} + \sum_{m=-\infty}^{+\infty} b_{\ell,m} H_m^{(2)}(kr_{\ell}) e^{jm\theta_{\ell}}$$

local incident field on cylinder C_{ℓ}
(i.e., primary + secondary incident field)

scattered field by cylinder C_{ℓ}

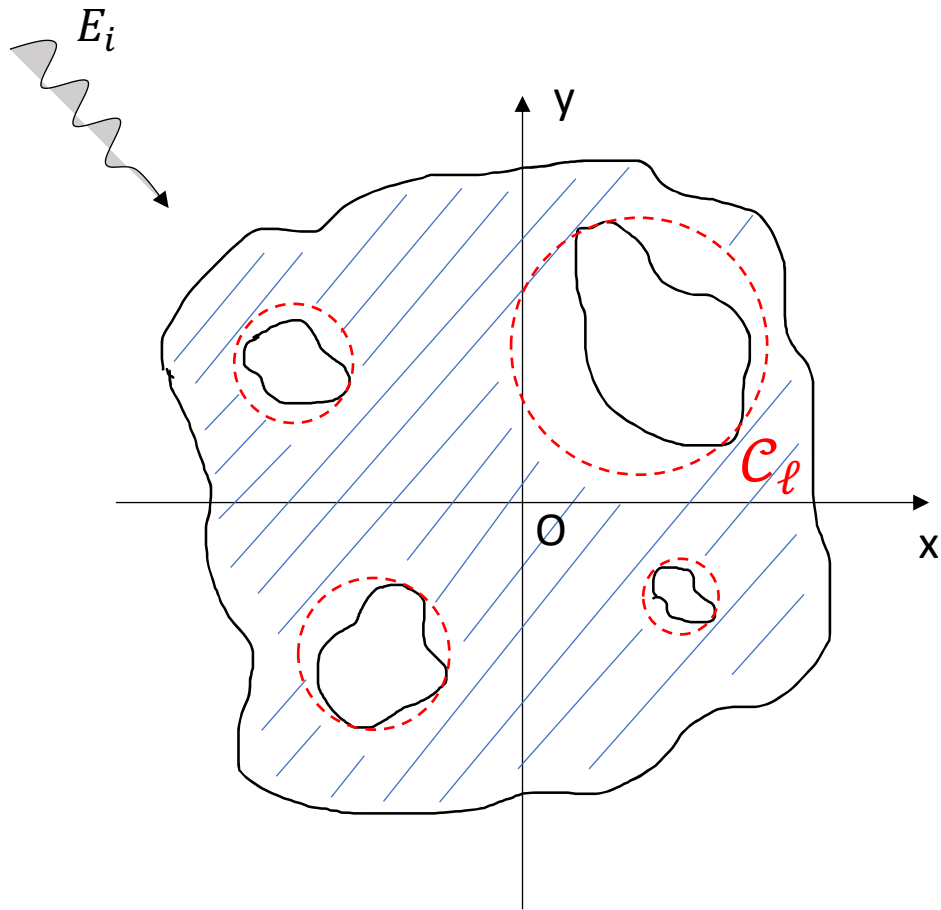
In a matrix form the interactions amongst
the different cylinders are described by:

$$\mathbf{a}_{\ell} = \mathbf{Q}_{\ell} + \sum_{i=1, i \neq \ell}^N \mathbf{T}_{i,\ell} \mathbf{b}_i$$

**LINEAR RELATIONSHIP
FOR EACH CYLINDER**

N being the number of inclusions

Multiple scatterers oriented tool: Scattering Matrix Method (SMM)



As one can write

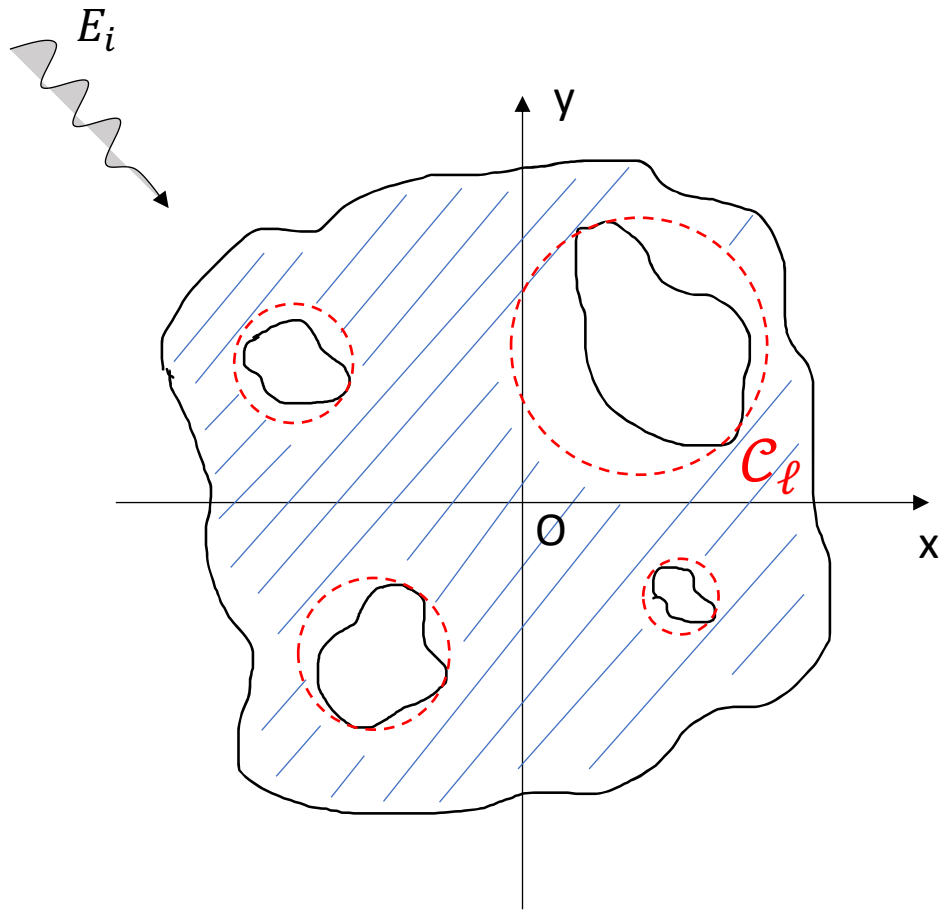
$$\mathbf{b}_\ell = \mathbf{S}_\ell \mathbf{a}_\ell$$

where \mathbf{S}_ℓ is the 'scattering matrix' of the inclusion, and depends on its characteristics

$$\mathbf{b}_\ell - \sum_{i=1, i \neq \ell}^N \mathbf{S}_\ell \mathbf{T}_{\ell,i} \mathbf{b}_i = \mathbf{S}_\ell \mathbf{Q}_\ell \quad \ell = 1, \dots, N$$

LINEAR SYSTEM IN THE UNKNOWN SCATTERING COEFFICIENTS \mathbf{b}_ℓ

Multiple scatterers oriented tool: Scattering Matrix Method (SMM)



$$\mathbf{b}_\ell - \sum_{i=1, i \neq \ell}^N \mathbf{S}_\ell \mathbf{T}_{\ell,i} \mathbf{b}_i = \mathbf{S}_\ell \mathbf{Q}_\ell \quad \ell = 1, \dots, N$$

- Specific scattering properties of each object are considered
- Coupling phenomena between objects are taken into account
- Computational complexity grows with the perimeters of the different inclusions (rather than with volume of the region under test)
- No staircasing errors

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- **Synthesis of EBG devices through the SMM**

formulation of the SMM

Let consider the expanded arrayal form of the linear system:

$$\begin{pmatrix} \mathbf{I} & -\mathbf{S}_1 \mathbf{T}_{1,2} & \cdots & -\mathbf{S}_1 \mathbf{T}_{1,N} \\ -\mathbf{S}_2 \mathbf{T}_{2,1} & \mathbf{I} & \cdots & -\mathbf{S}_2 \mathbf{T}_{2,N} \\ \cdots & \cdots & \cdots & \cdots \\ -\mathbf{S}_N \mathbf{T}_{N,1} & -\mathbf{S}_N \mathbf{T}_{N,2} & \cdots & \mathbf{I} \end{pmatrix} \begin{pmatrix} \mathbf{b}_1 \\ \mathbf{b}_2 \\ \cdots \\ \mathbf{b}_N \end{pmatrix} = \begin{pmatrix} \mathbf{S}_1 \mathbf{Q}_1 \\ \mathbf{S}_2 \mathbf{Q}_2 \\ \cdots \\ \mathbf{S}_N \mathbf{Q}_N \end{pmatrix}$$

and remember that [*]:

- the square matrix $\mathbf{T}_{l,i}$ of the (m,q) -th element $T_{l,i,m,q}$ takes into account the coupling mutual interactions
- the column matrix \mathbf{Q}_l of m -th element $Q_{l,m}$ represents the coefficients of the Fourier-Bessel expansion of primary incident fields
- the square matrix \mathbf{S}_l is the scattering matrix and depends on the parameters of the l -th cylinder
- the column matrix \mathbf{b}_l of m -th element $b_{l,m}$ represents the coefficients of the rigorous modal expansion of the scattered field

[*] D. Felbacq, et al., "Scattering by a random set of parallel cylinders", JOSA A 1994.

Inverse formulation of the SMM (I-SMM)

Let consider the expanded arrayal form of the linear system:

$$\begin{pmatrix} \mathbf{I} & -\mathbf{S}_1 \mathbf{T}_{1,2} & \cdots & -\mathbf{S}_1 \mathbf{T}_{1,N} \\ -\mathbf{S}_2 \mathbf{T}_{2,1} & \mathbf{I} & \cdots & -\mathbf{S}_2 \mathbf{T}_{2,N} \\ \cdots & \cdots & \cdots & \cdots \\ -\mathbf{S}_N \mathbf{T}_{N,1} & -\mathbf{S}_N \mathbf{T}_{N,2} & \cdots & \mathbf{I} \end{pmatrix} \begin{pmatrix} \mathbf{b}_1 \\ \mathbf{b}_2 \\ \cdots \\ \mathbf{b}_N \end{pmatrix} = \begin{pmatrix} \mathbf{S}_1 \mathbf{Q}_1 \\ \mathbf{S}_2 \mathbf{Q}_2 \\ \cdots \\ \mathbf{S}_N \mathbf{Q}_N \end{pmatrix}$$

CONCEPTUAL DESIGN PROBLEM

Determine cylinders' parameters able to behave like a desired device.

MATHEMATICAL DESIGN PROBLEM

Determine \mathbf{S}_l and \mathbf{b}_l able to scatter a given field on a given surface.

Inverse formulation of the SMM (I-SMM)

The (new) inverse scattering equations

$$\begin{pmatrix} \mathbf{I} & -\mathbf{S}_1 \mathbf{T}_{1,2} & \cdots & -\mathbf{S}_1 \mathbf{T}_{1,N} \\ -\mathbf{S}_2 \mathbf{T}_{2,1} & \mathbf{I} & \cdots & -\mathbf{S}_2 \mathbf{T}_{2,N} \\ \cdots & \cdots & \cdots & \cdots \\ -\mathbf{S}_N \mathbf{T}_{N,1} & -\mathbf{S}_N \mathbf{T}_{N,2} & \cdots & \mathbf{I} \end{pmatrix} \begin{pmatrix} \mathbf{b}_1 \\ \mathbf{b}_2 \\ \cdots \\ \mathbf{b}_N \end{pmatrix} = \begin{pmatrix} \mathbf{S}_1 \mathbf{Q}_1 \\ \mathbf{S}_2 \mathbf{Q}_2 \\ \cdots \\ \mathbf{S}_N \mathbf{Q}_N \end{pmatrix} \quad \text{state equation}$$

$$E_s(R, \theta) = \sum_{i=1}^N \sum_{m=-M}^{+M} b_{i,m} H_m^{(2)}(\beta R) e^{jm\theta}, \quad R \notin \text{cylinders} \quad \text{data equation}$$

wherein $\mathbf{S}_n = \begin{pmatrix} S_{-M} & 0 & 0 & 0 & 0 \\ 0 & \ddots & 0 & 0 & 0 \\ 0 & 0 & s_m & 0 & 0 \\ 0 & 0 & 0 & \ddots & 0 \\ 0 & 0 & 0 & 0 & S_M \end{pmatrix}$ and s_m depends on the kind of inclusion (dielectric, metallic, magnetics,..) and its dimension

Design procedure

Determine inclusions D_i such to

$$\Phi = \min_{D_i, \tau} \frac{\|E_{tot}(\underline{r}) - E_{tot}^{specified}(\underline{r})\|_{\Gamma}^2}{\|E_{tot}^{specified}(\underline{r})\|_{\Gamma}^2}$$

subject to desired constraints on D_i .

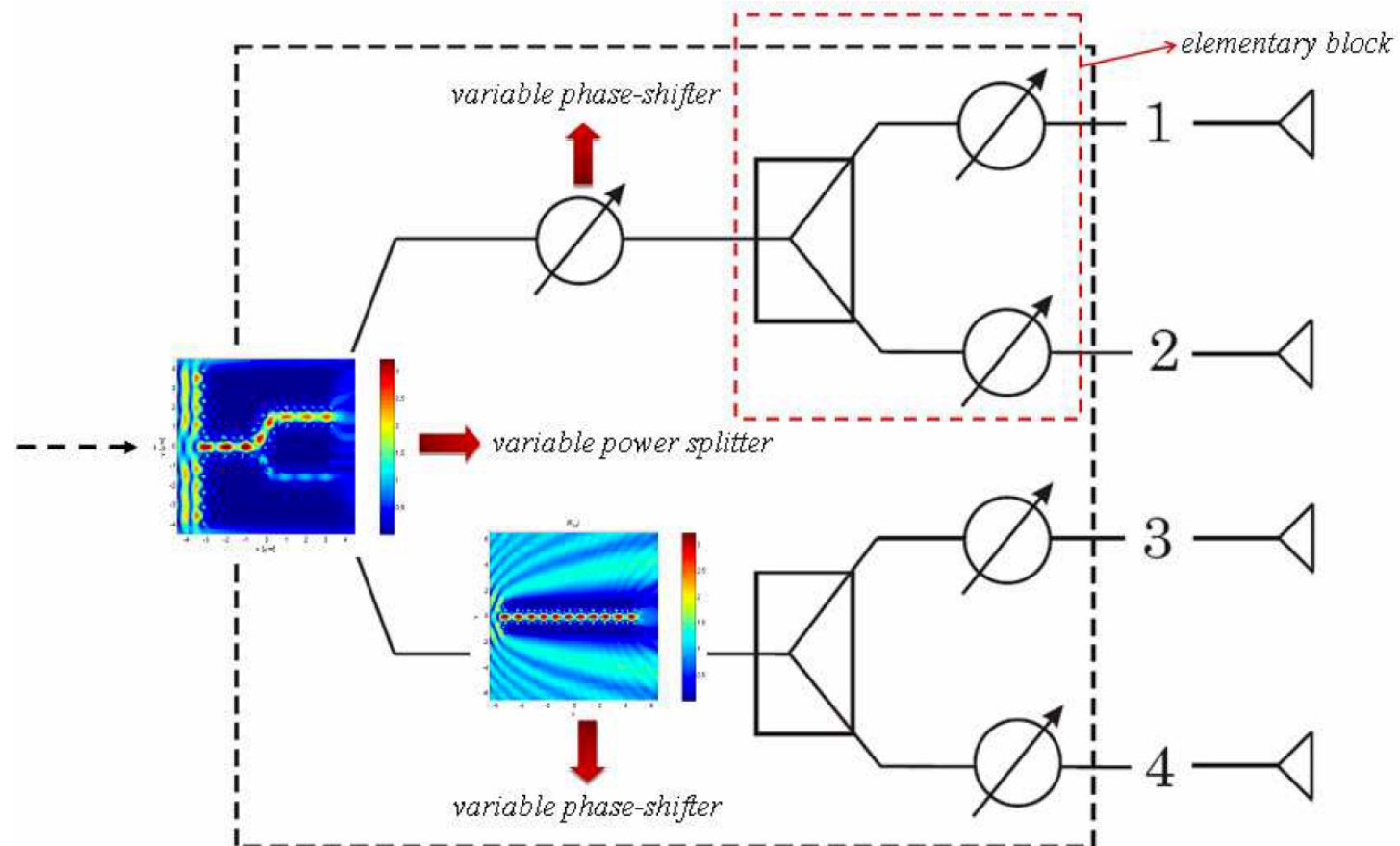
N.B.1. D_i could mean permittivity, radius, both ones, ...

N.B.2. Favourable starting points are needed to find a satisfying solution

Numerical Assessment

Design of a beam-forming network for
antennas array

Design of a beam-forming network for antennas array

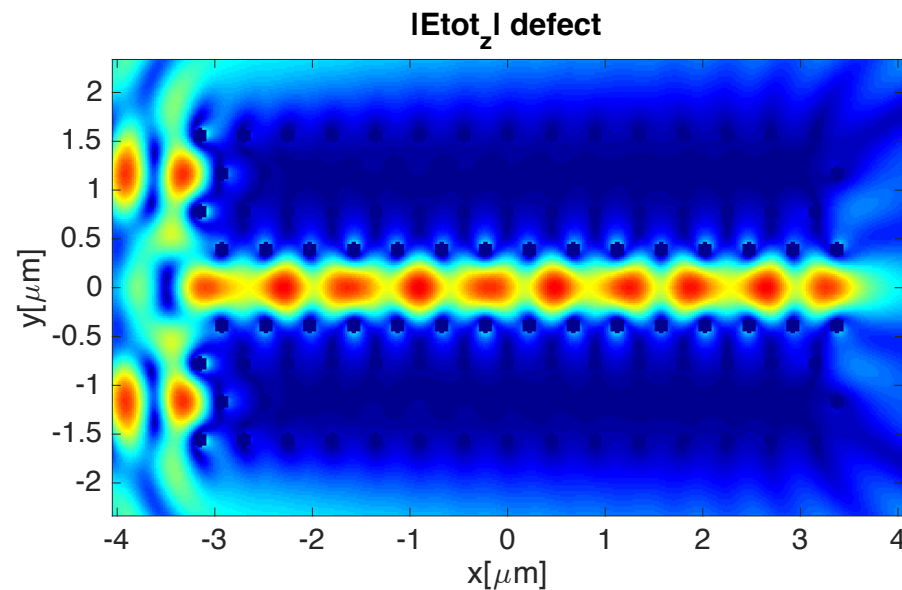
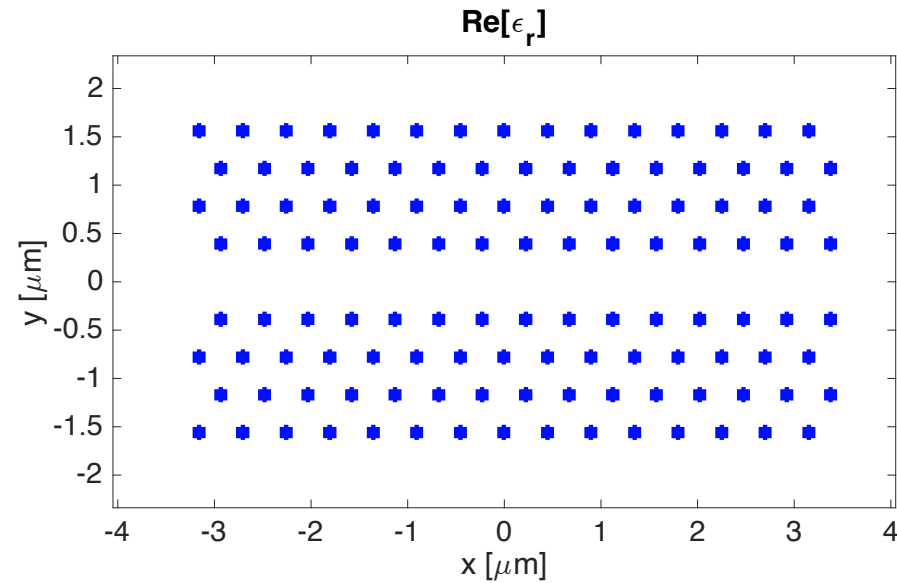
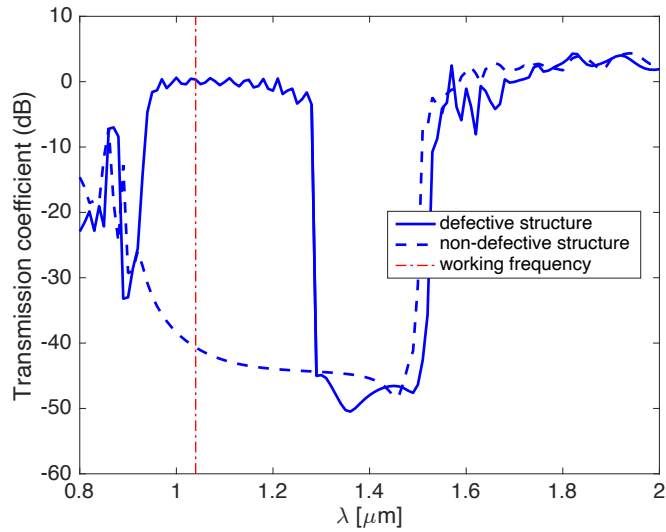


Numerical Assessment

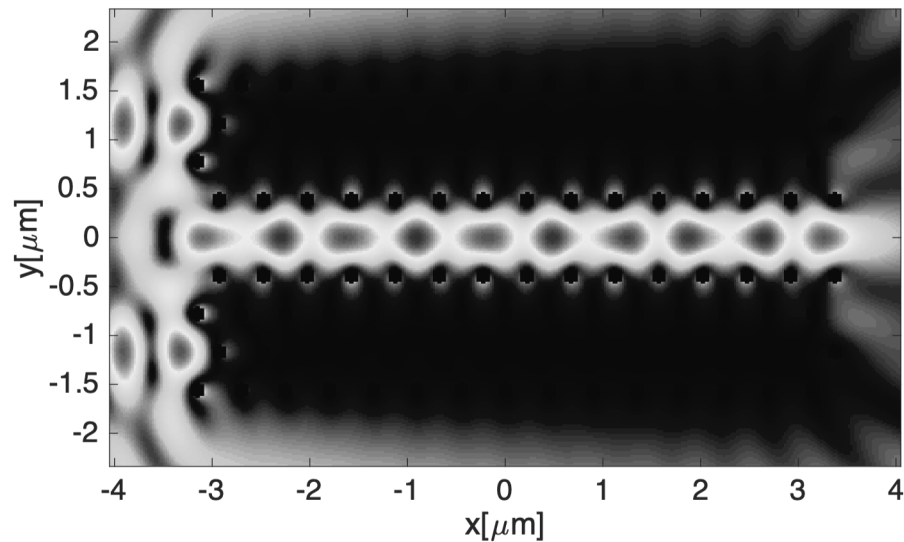
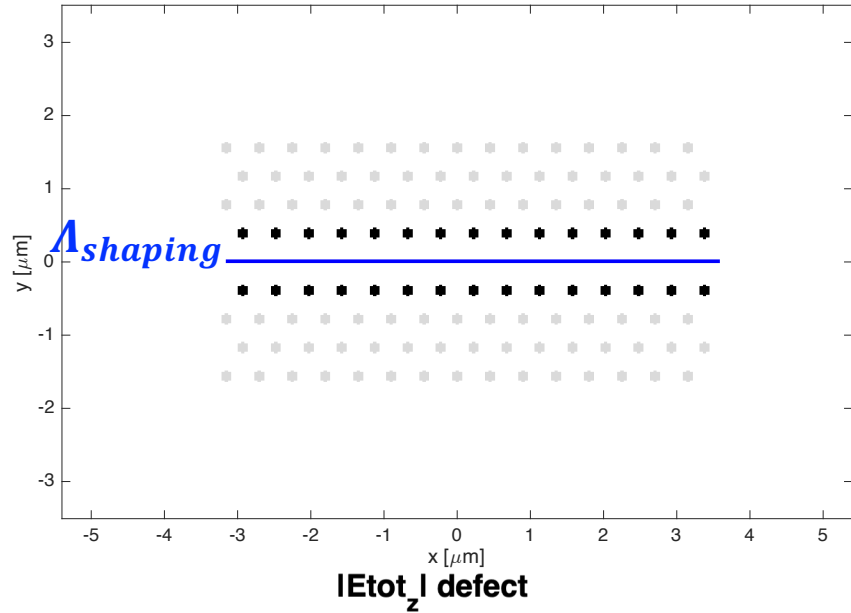
Design of a beam-forming network for
antennas array

Optimization of basic elements

Basic element #1: EBG straight waveguide



Basic element #1: EBG straight waveguide



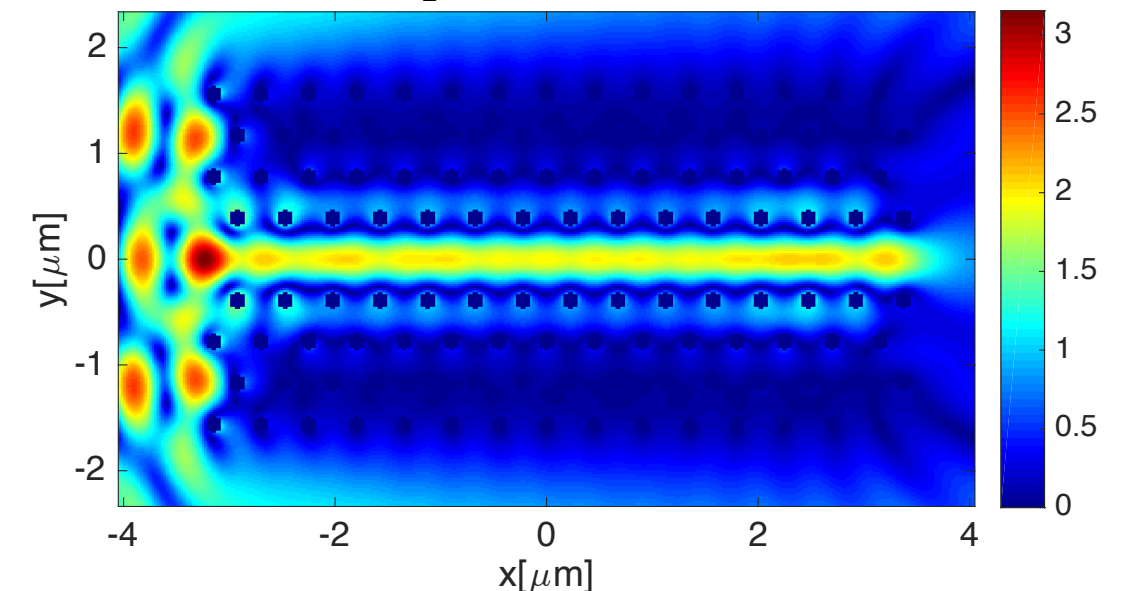
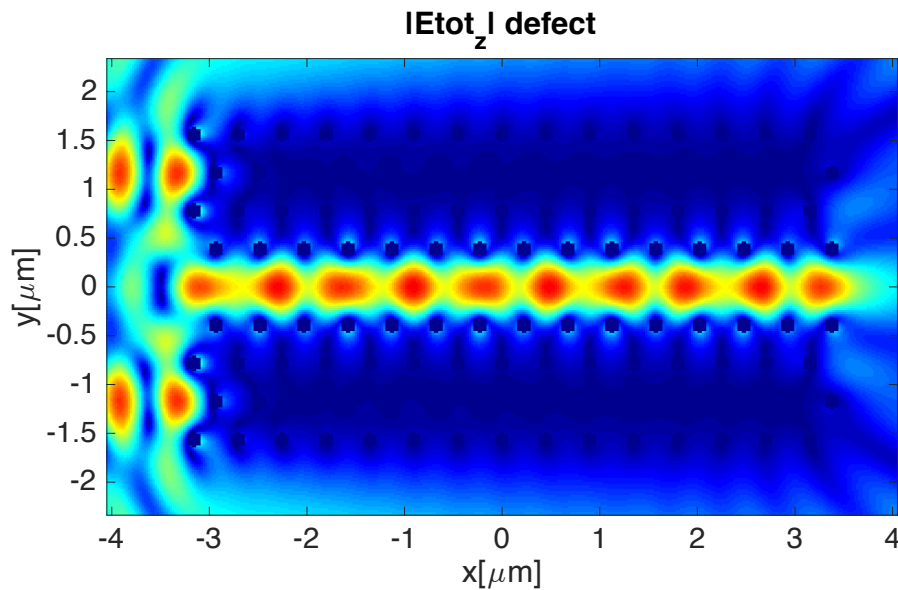
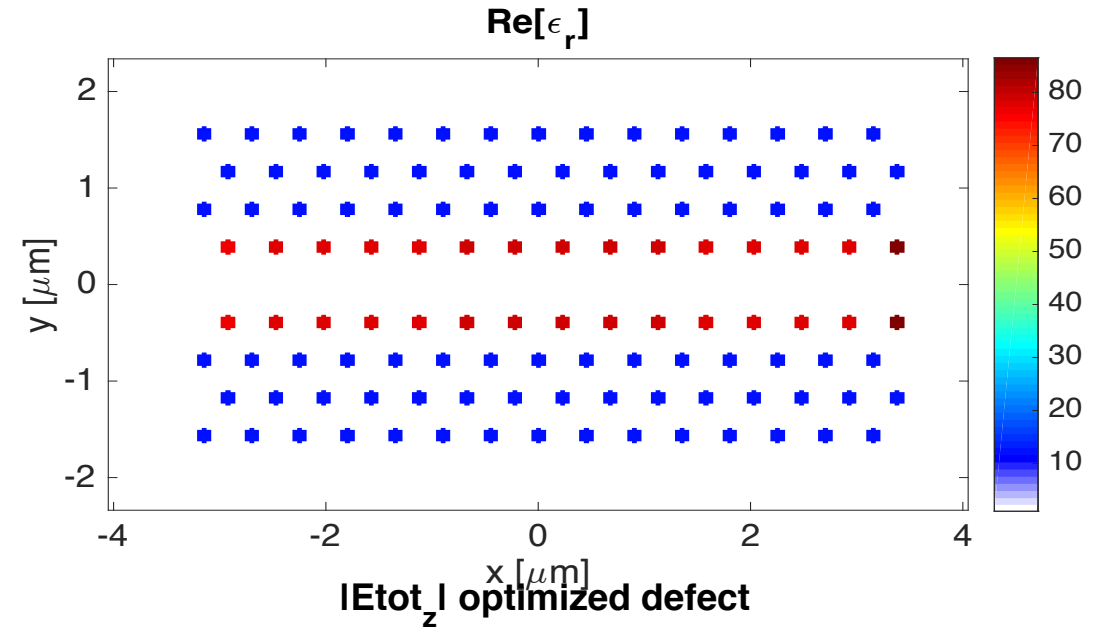
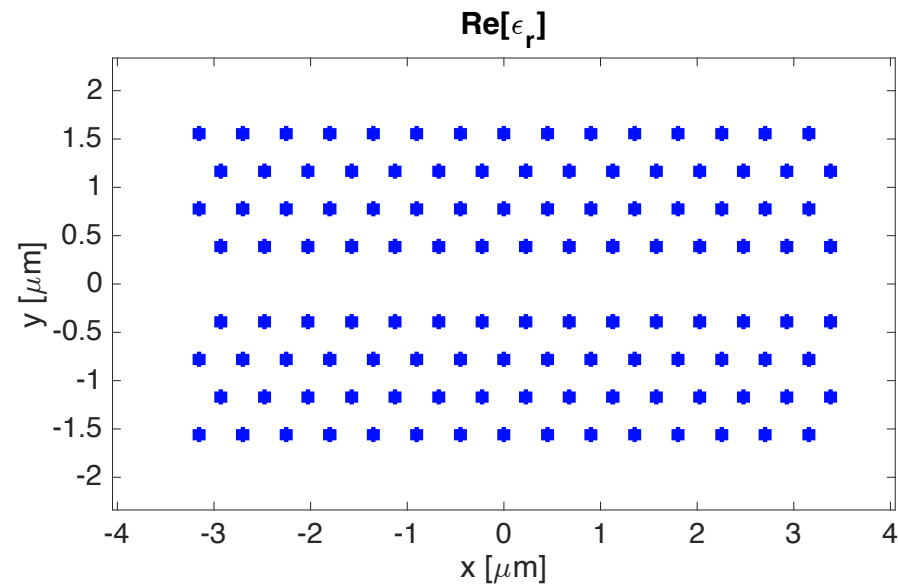
OPTIMIZATION PROBLEM

$$\min_{\epsilon_r} \left\{ \frac{\max |E_{tot}| - \min |E_{tot}|}{2} \right\}_{\Lambda_{shaping}}$$

subject to

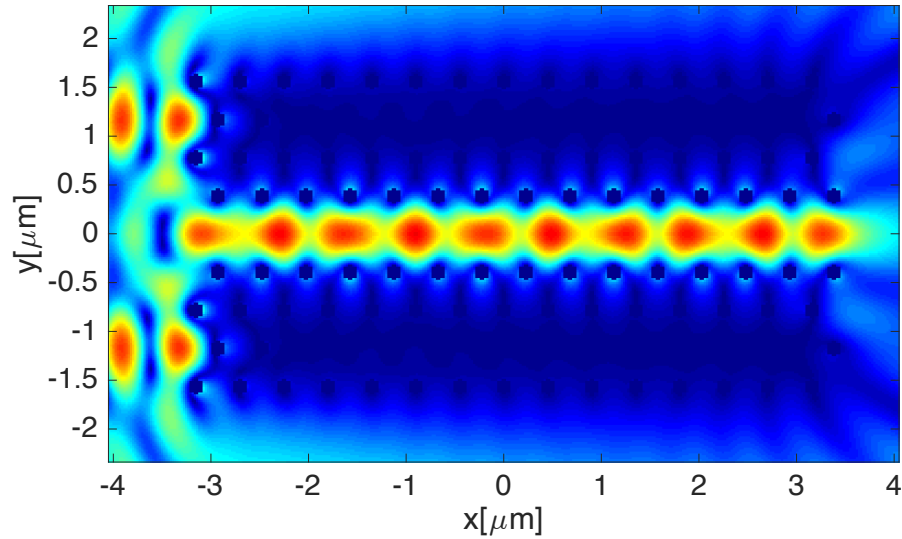
$$\epsilon_r^{up} = \epsilon_r^{down}$$

Basic element #1: EBG straight waveguide



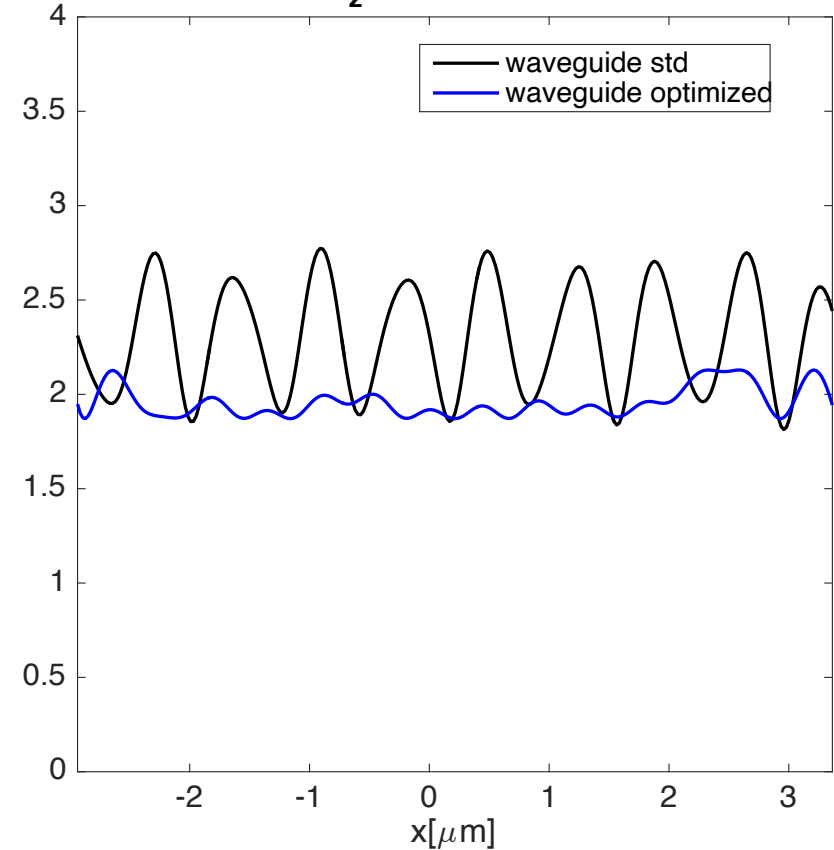
Basic element #1: EBG straight waveguide

$|E_{tot_z}|$ defect

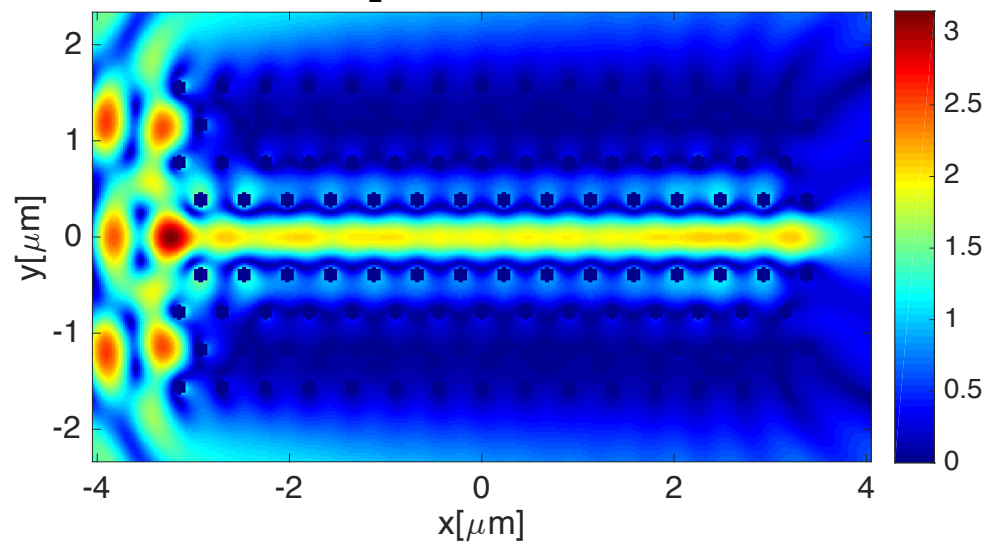


ripple = 0.4801

$|E_{tot_z}|$ in input channel

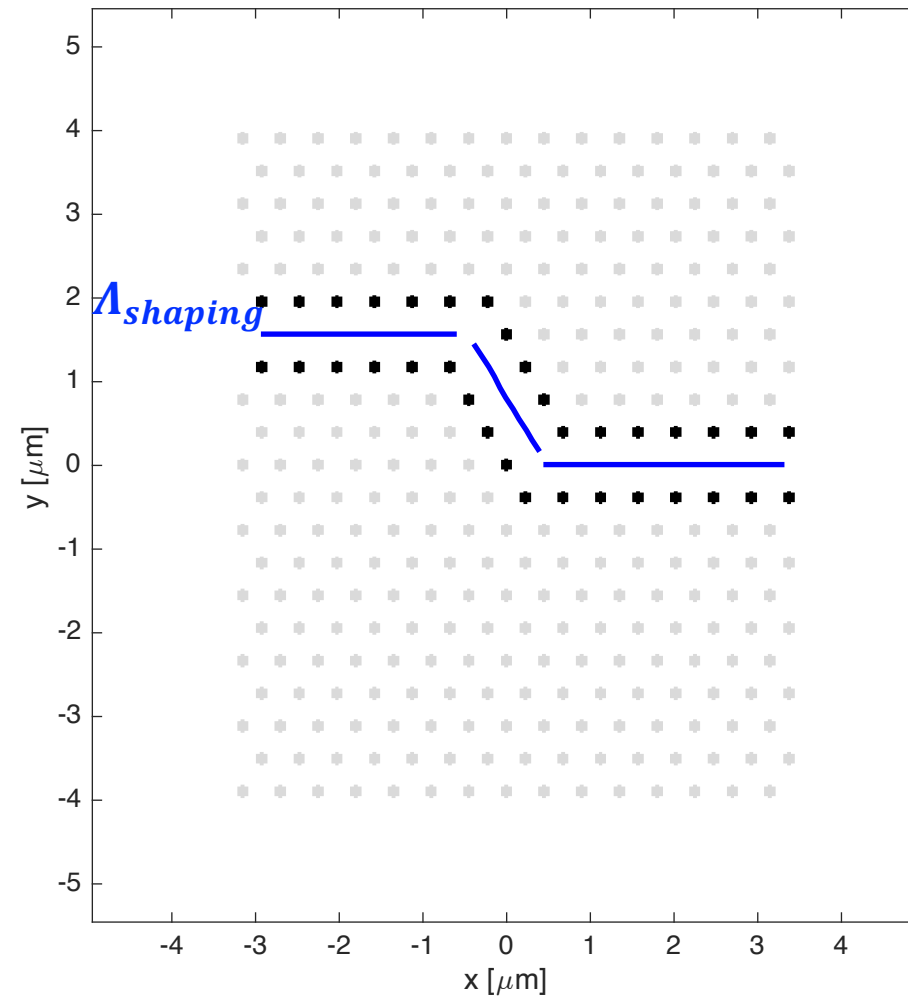


$|E_{tot_z}|$ optimized defect



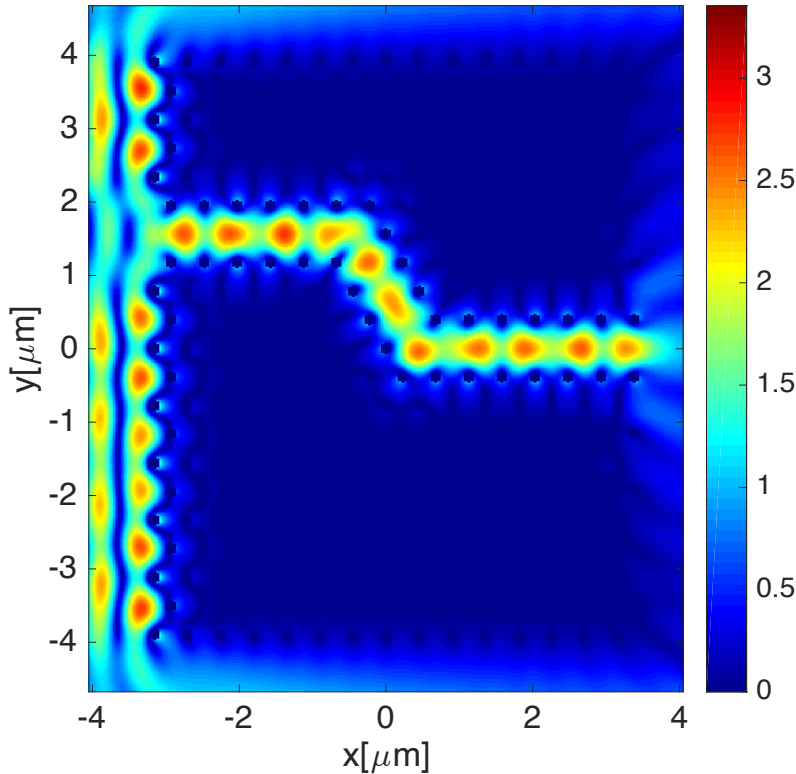
ripple = 0.1289

Basic element #2: 60° bend EBG waveguide

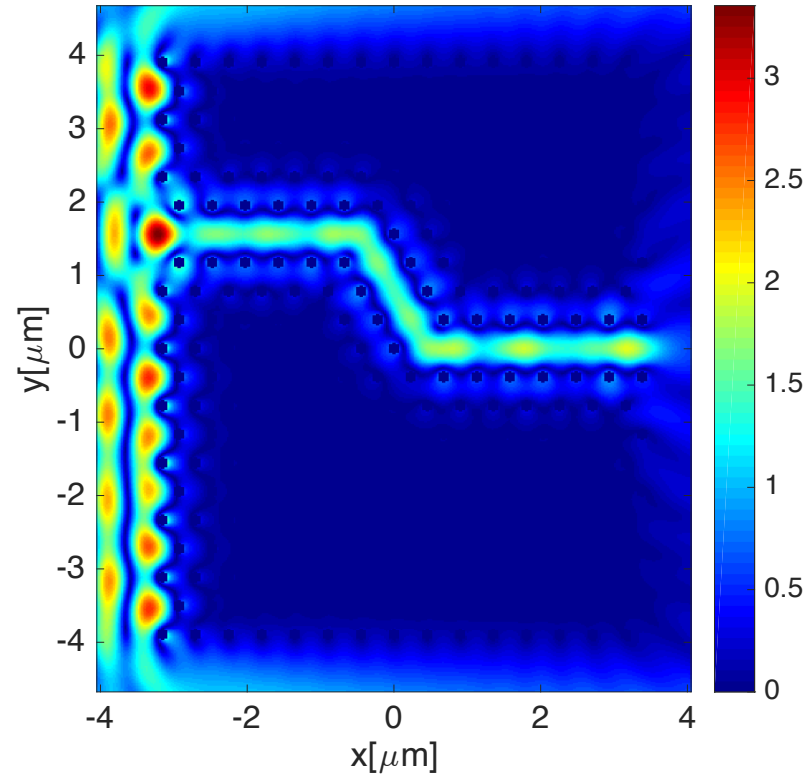


Basic element #2: 60° bend EBG waveguide

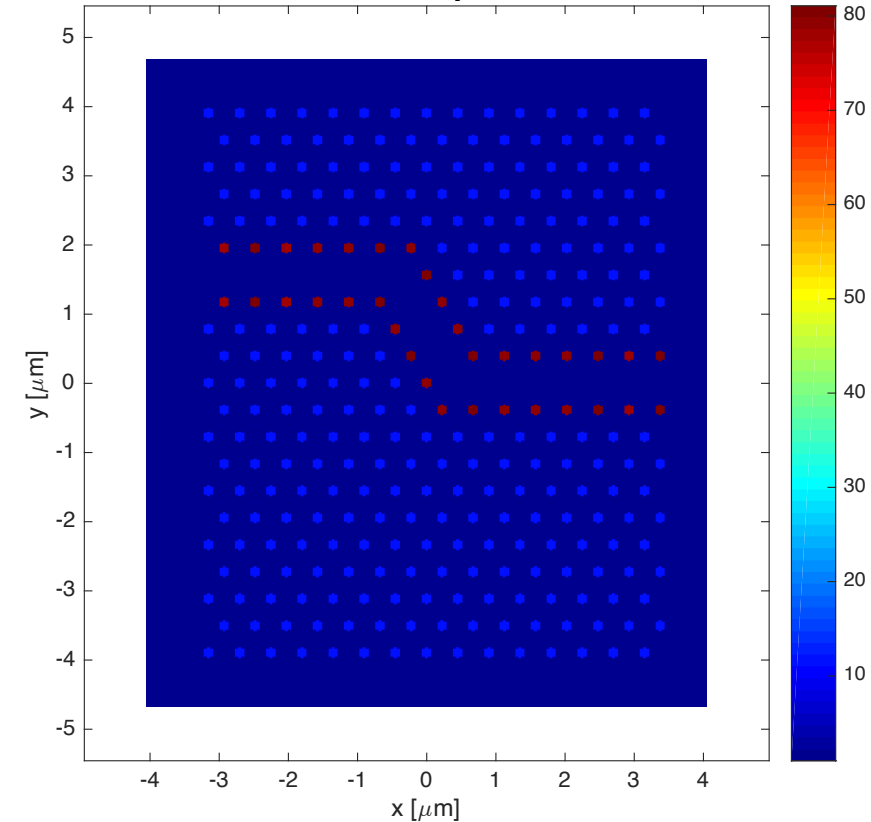
$|E_{tot,z}|$ defect



$|E_{tot,z}|$ optimized defect



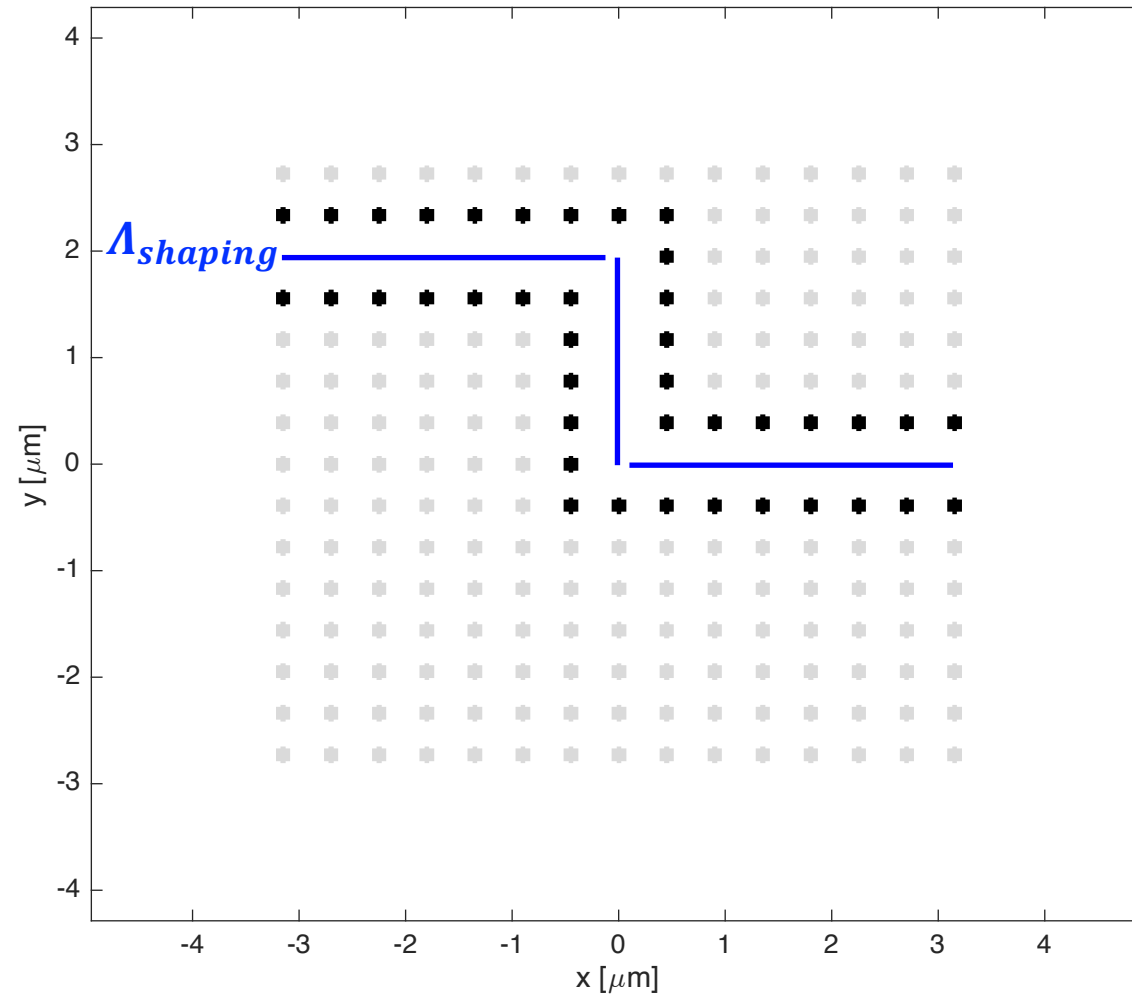
$\text{Re}[\epsilon_r]$



ripple_INPUT_channel = 0.4455
ripple_OBLIQUE_channel = 0.4459
ripple_OUTPUT_channel = 0.4380

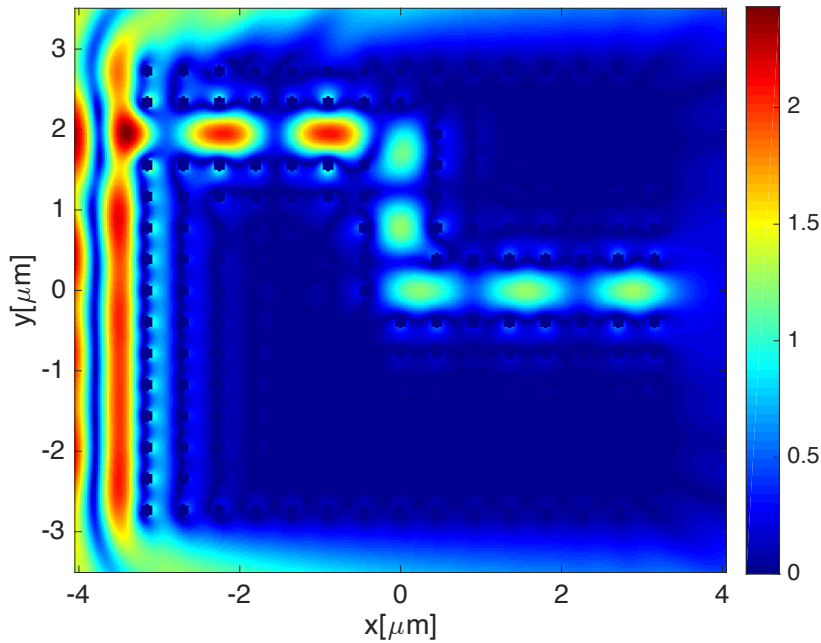
ripple_INPUT_channel = 0.2459
ripple_OBLIQUE_channel = 0.1090
ripple_OUTPUT_channel = 0.3573

Basic element #3: 90° bend EBG waveguide

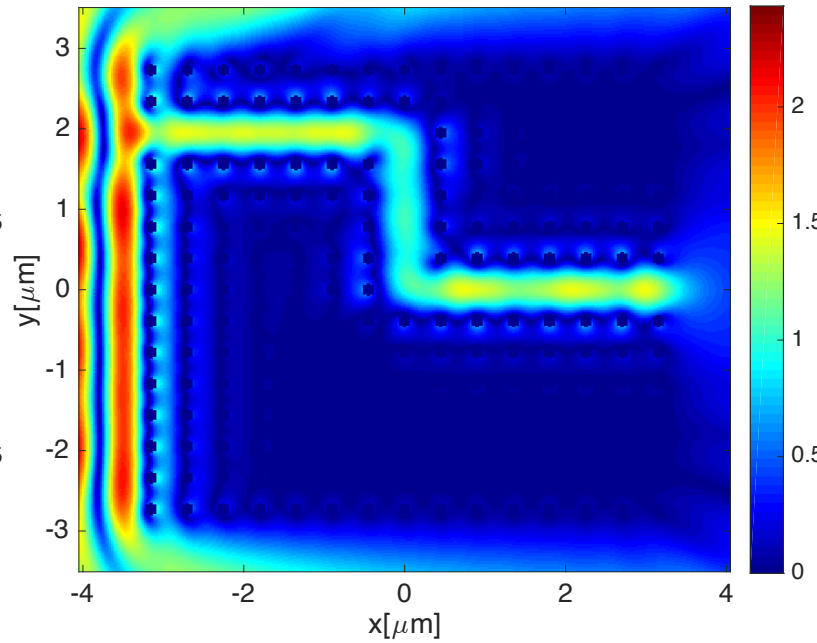


Basic element #3: 90° bend EBG waveguide

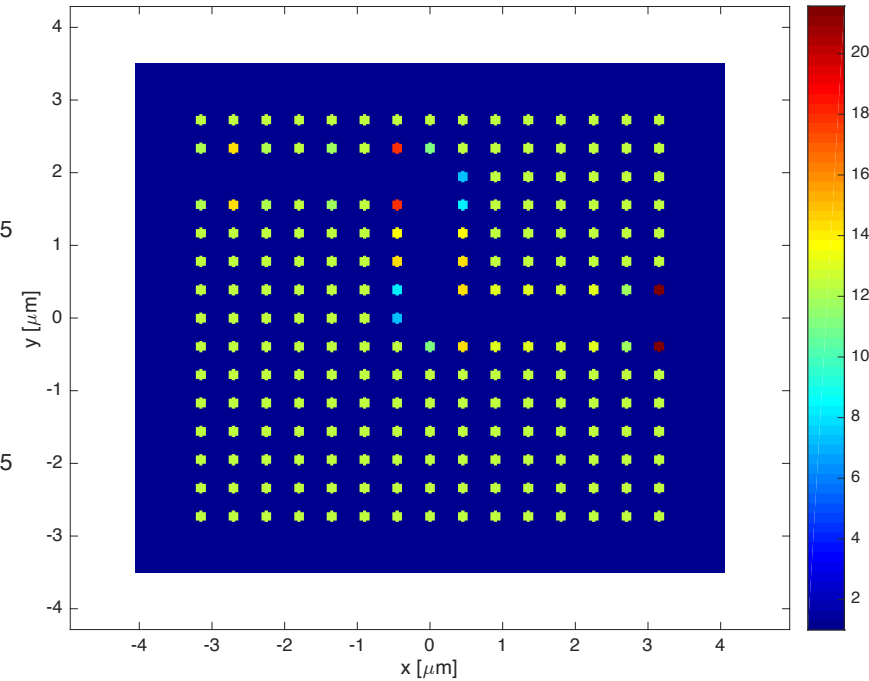
$|E_{tot,z}|$ defect



$|E_{tot,z}|$ optimized defect



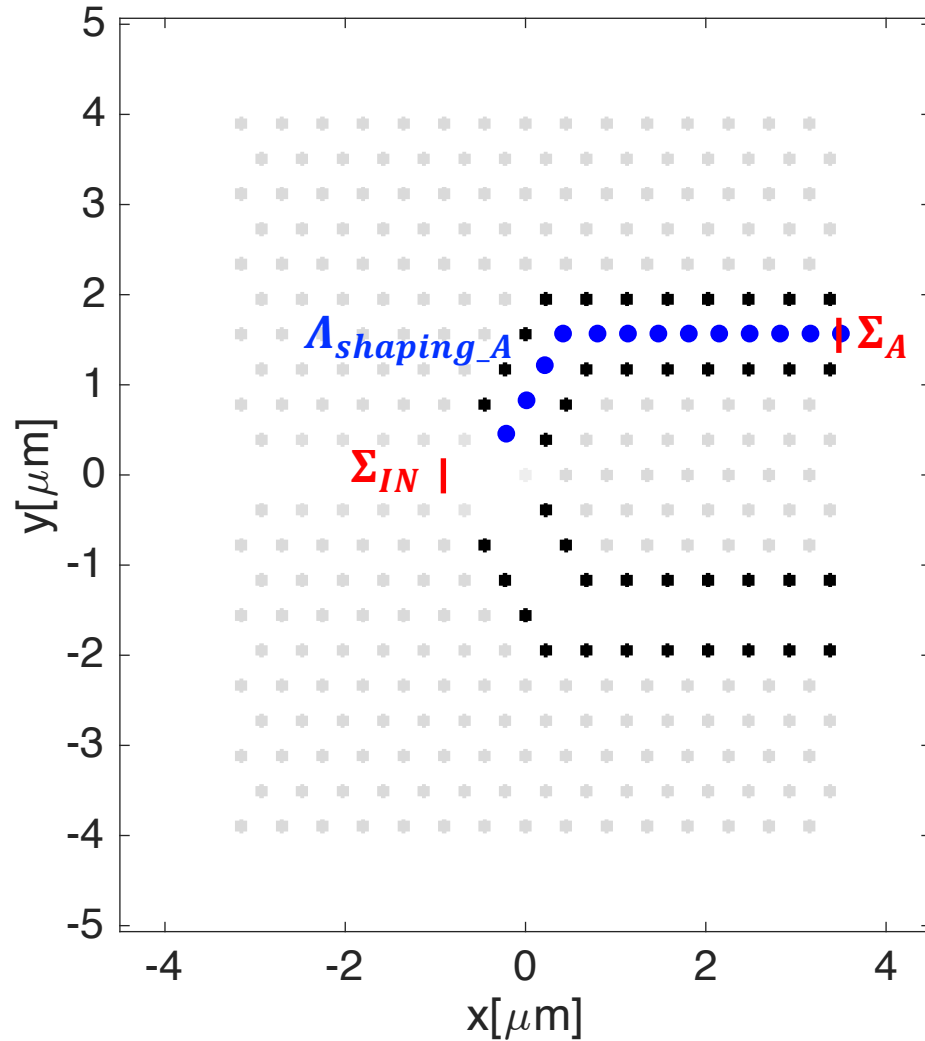
$\text{Re}[\epsilon_r]$



ripple_INPUT_channel = 0.8641
ripple_VERTICAL_channel = 0.4762
ripple_OUTPUT_channel = 0.3829

ripple_INPUT_channel = 0.2349
ripple_VERTICAL_channel = 0.0556
ripple_OUTPUT_channel = 0.1985

Basic element #4: 50-50 EBG power splitter



OPTIMIZATION PROBLEM

$$\min_{\varepsilon_r} \left\{ \text{Ripple}_{\Lambda_{shaping_A}} \right\}$$

subject to

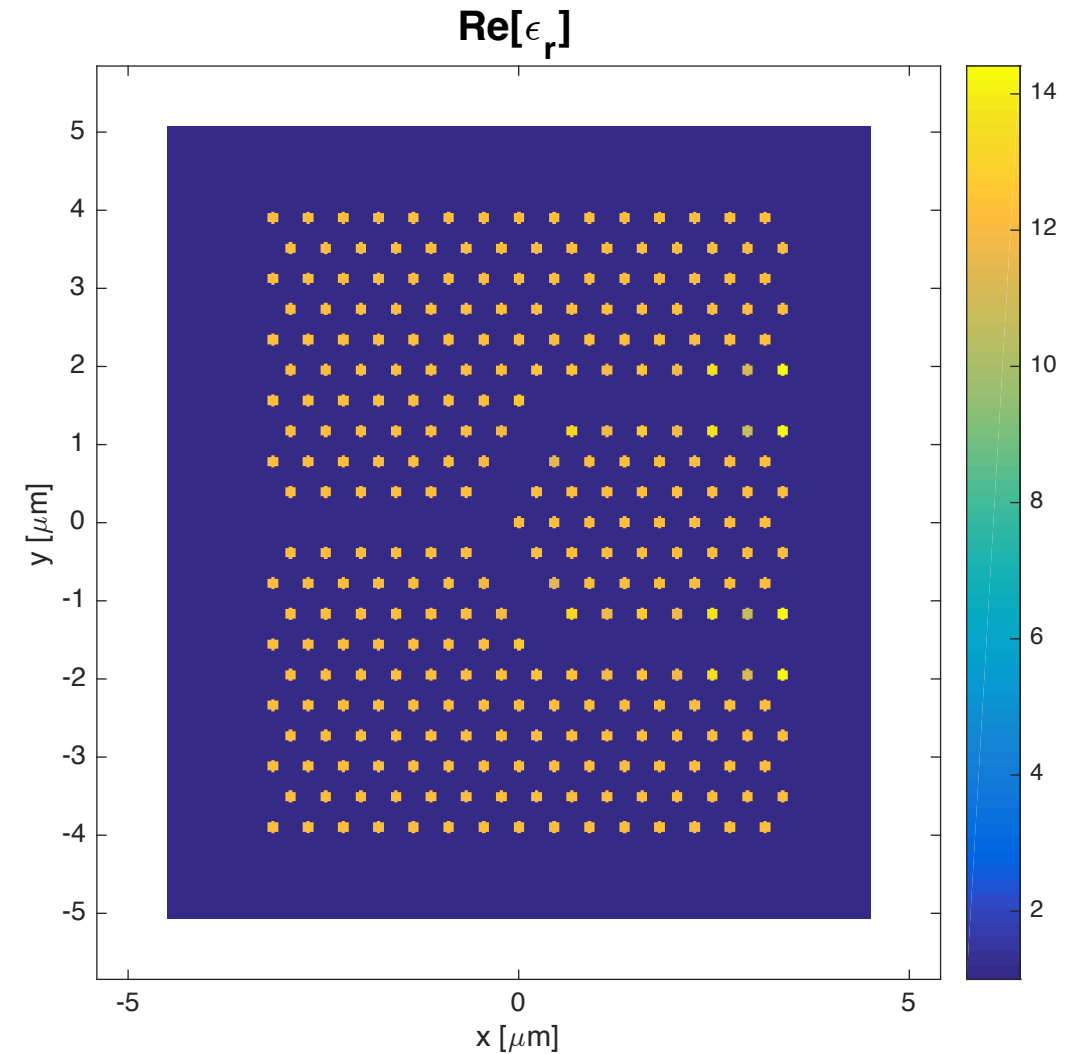
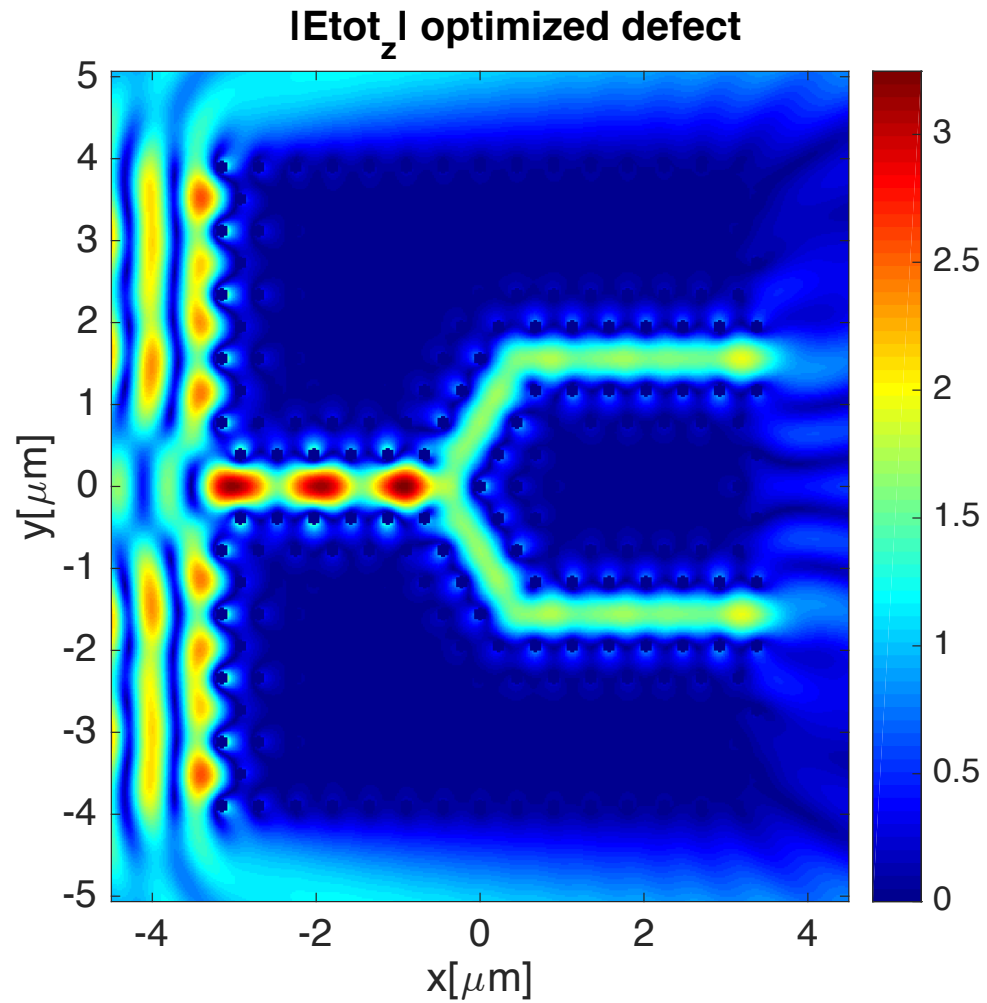
$$\varepsilon_r^{up} = \varepsilon_r^{down}$$

$$\varepsilon_r \geq 1$$

$$\left\| \phi_{\Sigma_A} - 0.5 \phi_{\Sigma_{IN}} \right\|_2 \leq 0.001$$

Basic element #4: 50-50 EBG power splitter

ripple = 0.2545



Conclusions

- **Inverse scattering theory and solution procedures can be used as convenient and flexible design tool.**
- **A new suitable and efficient design tool based on the Scattering Matrix Method has been proposed and preliminary assessed**
 - *The method is roughly two orders of magnitude faster than the previous full wave method;*
 - *Classes of possible inclusions and objective functions can be exploited.*
- **Future works: other devices** (*for instance, EBG phase shifter, 75-25 power splitter, ...*), **other inclusion shapes** (*for instance elliptical*), **unknown arrangements.**



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